PRELIMINARY

HYUNDAI SEMICONDUCTOR HY514100

4M×1-Bit CMOS DRAM

M191200A-MAY91

T-46-23-15

DESCRIPTION

The HY514100 is a low power and new generation dynamic RAM organized 4,194,304 words by 1 bit. The HY514100 utilizes HYUNDAI's CMOS process technology as well as advanced circuit technology to provide wide operating margins and very low power to the user.

The package size provides high system bit densities and is compatible with widely available automated testing and insertion equipment.

All inputs and outputs are TTL compatible. Input and output capacitances are significantly lowered to allow increased system performance.

FEATURES

- **Low power dissipation**
  - **Operating Current, 100ns : 80mA(max.)**
  - **TTL Standby Current : 2mA(max.)**
  - **CMOS Standby Current : 1mA(max.)**
- **Read-Modify-Write Capability**
- **$\overline{RAS}$-only, Hidden, $\overline{CAS}$-Before-$\overline{RAS}$ Refresh Capability**
- **Common I/O capability**
- **Fast Page mode and Test mode capability**
- **1024 refresh cycles/16 ms**
- **High reliability 300 mil 20/26 pin SOJ and 20/26 pin TSOP**
- **Fast access time and cycle time (ns)**

	HY514100-80	HY514100-10
Max $\overline{RAS}$ Access Time, t_{RAC}	80	100
Max $\overline{CAS}$ Access Time, t_{CAC}	25	25
Min Fast Page Mode Cycle Time, t_{PC}	55	60
Min Cycle Time, t_{RC}	150	180

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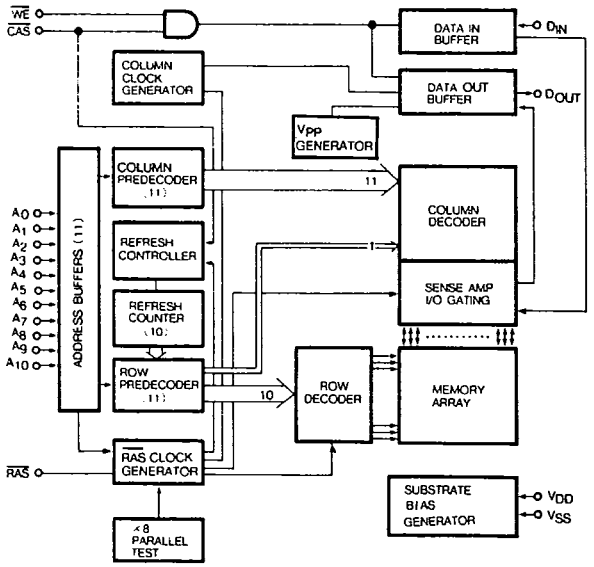
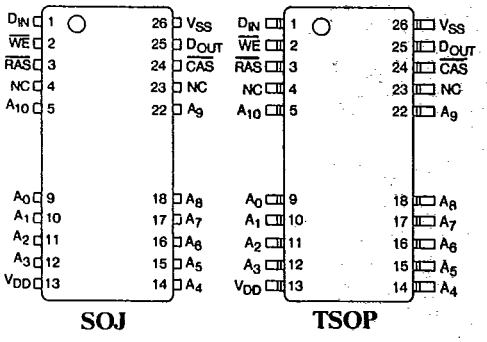
BLOCK DIAGRAM



PIN CONNECTIONS



PIN NAMES

$\overline{RAS}$	ROW ADDRESS STROBE
$\overline{CAS}$	COLUMN ADDRESS STROBE
$\overline{WE}$	WRITE ENABLE
A_0-A_{10}	ADDRESS INPUT
D_{IN}	DATA INPUT
D_{OUT}	DATA OUTPUT
V_{DD}	POWER(+5V)
V_{SS}	GROUND

ABSOLUTE MAXIMUM RATINGS

SYMBOL	PARAMETER	RATING	UNIT
T_A	Ambient Temperature	0 to 70	°C
T_{STG}	Storage Temperature	−55 to 150	°C
V_{IN}, V_{OUT}	Voltage on Any Pin Relative to V_{SS}	−1.0 to 7.0	V
V_{DD}	Voltage on V_{DD} Relative to V_{SS}	−1.0 to 7.0	V
I_{OS}	Short Circuit Output Current	50	mA
P_T	Power Dissipation	0.6	W

NOTE : Operation at or above Absolute Maximum Ratings can adversely affect device reliability.

RECOMMENDED OPERATING CONDITIONS

(T_A=0°C to 70°C)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V_{DD}	Supply Voltage	4.5	5.0	5.5	V
V_{IH}	Input Hight Voltage	2.4	–	V_{DD}+1	V
V_{IL}	Input Low Voltage	−1.0	–	0.8	V

NOTE : All voltages are reference to V_{SS}.

DC CHARACTERISTICS

(T_A=0°C to 70°C, V_{DD}=5V± 10%, V_{SS}=0V, unless otherwise noted)

SYMBOL	PARAMETER	TEST CONDITIONS	STEED	HYM514100		UNIT	NOTE
				MIN.	MAX.		
$\|I_{LI}\|$	Input Leakage Current(any input pin)	0V ≤V_{IN} ≤ 6.5V, All other pin not under test= V_{SS}			10	μA	
$\|I_{LO}\|$	Output Leakage Current for High Impedance State	D_{OUT} is disable, 0V ≤ V_{OUT} ≤ 5.5V			10	μA	
I_{DD1}	V_{DD} Supply Current, Operating	$\overline{RAS}$, $\overline{CAS}$, Address cycling, t_{RC}=t_{RC}(min.)	−80		90	mA	1, 2
			−10		80		
I_{DD2}	V_{DD} Supply Current, TTL Standby	$\overline{RAS}$=$\overline{CAS}$=V_{IH}			2	mA	
I_{DD3}	V_{DD} Supply Current, $\overline{RAS}$-only Refresh	$\overline{RAS}$ cycling, $\overline{CAS}$=V_{IH}, t_{RC}=t_{RC}(min.)	−80		90	mA	2
			−10		80		
I_{DD4}	V_{DD} Supply Current, Fast page mode	$\overline{RAS}$=V_{IL}, Address cycling, t_{PC}=t_{PC}(min.)	−80		50	mA	1, 2
			−10		40		
I_{DD5}	V_{DD} Supply Current, CMOS Standby	$\overline{RAS}$=$\overline{CAS}$=V_{DD}−0.2V			1	mA	
I_{DD6}	V_{DD} Supply Current, $\overline{CAS}$-Before-$\overline{RAS}$ Refresh	$\overline{RAS}$, $\overline{CAS}$ cycling t_{RC}=t_{RC}(min.)	−80		90	mA	2
			−10		80		
V_{OL}	Output Low Voltage	I_{OL}=4.2mA			0.4	V	
V_{OH}	Output High Voltage	I_{OH}=−5mA		2.4		V	

NOTES :
1. I_{DD1} and I_{DD4} depend on output loading, specified values are obtained with the output open.
2. I_{DD1}, I_{DD3}, I_{DD4} and I_{DD6} depend on cycle rate.

AC CHARACTERISTICS

(T_A=0°C to 70°C, V_{DD}=5V± 10%, V_{SS}=0V, unless otherwise noted.) NOTES : 1, 2, 3

#	SYMBOL	PARAMETER	HY514100				UNIT	NOTES
			80		10			
			MIN.	MAX.	MIN.	MAX.		
1	t_{RC}	Random Read or Write Cycle Time	150	–	180	–	ns	
2	t_{RWC}	Read-Modify-Write Cycle Time	180	–	210	–	ns	
3	t_{PC}	Fast Page Mode Cycle Time	55	–	60	–	ns	
4	t_{PRWC}	Fast Page Mode Read-Modify-Write Cycle Time	85	–	90	–	ns	
5	t_{RAC}	Access Time from $\overline{RAS}$	–	80	–	100	ns	4, 9
6	t_{CAC}	Access Time from $\overline{CAS}$	–	25	–	25	ns	4, 9
7	t_{AA}	Access Time from Column Address	–	40	–	45	ns	4, 9
8	t_{CPA}	Access Time from $\overline{CAS}$ Precharge	–	50	–	55	ns	4
9	t_{CLZ}	$\overline{CAS}$ to Output in Low-Z	0	–	0	–	ns	4
10	t_{OFF}	Output Buffer Turn-off Delay	0	20	0	20	ns	5
11	t_T	Transition Time (Rise and Fall)	3	50	3	50	ns	3
12	t_{RP}	$\overline{RAS}$ Precharge Time	60	–	70	–	ns	
13	t_{RAS}	$\overline{RAS}$ Pulse Width	80	10K	100	10K	ns	
14	t_{RASP}	$\overline{RAS}$ Pulse Width(Fast Page Mode)	80	200K	100	200K	ns	
15	t_{RSH}	$\overline{RAS}$ Hold Time	25	–	25	–	ns	
16	t_{CSH}	$\overline{CAS}$ Hold Time	80	–	100	–	ns	
17	t_{CAS}	$\overline{CAS}$ Pulse Width	25	10K	25	10K	ns	
18	t_{RCD}	$\overline{RAS}$ to $\overline{CAS}$ Delay Time	20	55	25	75	ns	9
19	t_{RAD}	$\overline{RAS}$ to Column Address Delay Time	15	40	20	55	ns	10
20	t_{CRP}	$\overline{CAS}$ to $\overline{RAS}$ Precharge Time	5	–	10	–	ns	
21	t_{CP}	$\overline{CAS}$ Precharge Time	10	–	10	–	ns	
22	t_{ASR}	Row Address Set-up Time	0	–	0	–	ns	
23	t_{RAH}	Row Address Hold Time	10	–	15	–	ns	
24	t_{ASC}	Column Address Set-up Time	0	–	0	–	ns	
25	t_{CAH}	Column Address Hold Time	15	–	20	–	ns	
26	t_{AR}	Column Address Hold Time referenced to $\overline{RAS}$	60	–	80	–	ns	
27	t_{RAL}	Column Address to $\overline{RAS}$ Lead Time	40	–	45	–	ns	
28	t_{RCS}	Read Command Set-up Time	0	–	0	–	ns	
29	t_{RCH}	Read Command Hold Time	0	–	0	–	ns	
30	t_{RRH}	Read Command Hold Time referenced to $\overline{RAS}$	0	–	0	–	ns	
31	t_{WCH}	Write Command Hold Time	15	–	20	–	ns	
32	t_{WCR}	Write Command Hold Time referenced to $\overline{RAS}$	60	–	80	–	ns	
33	t_{WP}	Write Command Pulse Width	15	–	20	–	ns	
34	t_{RWL}	Write Command to $\overline{RAS}$ Lead Time	25	–	25	–	ns	
35	t_{CWL}	Write Command to $\overline{CAS}$ Lead Time	25	–	25	–	ns	
36	t_{DS}	Data Set-up Time	0	–	0	–	ns	7
37	t_{DH}	Data Hold Time	15	–	20	–	ns	7
38	t_{DHR}	Data Hold Time referenced to $\overline{RAS}$	60	–	80	–	ns	
39	t_{REF}	Refresh Period	–	16	–	16	ms	
40	t_{WCS}	Write Command Set-up Time	0	–	0	–	ns	8
41	t_{CWD}	$\overline{CAS}$ to $\overline{WE}$ Delay Time	25	–	25	–	ns	8
42	t_{RWD}	$\overline{RAS}$ to $\overline{WE}$ Delay Time	80	–	100	–	ns	8
43	t_{AWD}	Column Address to $\overline{WE}$ Delay Time	40	–	45	–	ns	8

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#	SYMBOL	PARAMETER	HY514100				UNIT	NOTES
			80		10			
			MIN.	MAX.	MIN.	MAX.		
44	t_{CSR}	$\overline{CAS}$ Set-up Time ($\overline{CAS}$ Before $\overline{RAS}$ Cycle)	10	–	10	–	ns	
45	t_{CHR}	$\overline{CAS}$ Hold Time ($\overline{CAS}$ Before $\overline{RAS}$ Cycle)	30	–	30	–	ns	
46	t_{RPC}	$\overline{RAS}$ to $\overline{CAS}$ Precharge Time	0	–	0	–	ns	
47	t_{CPT}	$\overline{CAS}$ Precharge Time($\overline{CAS}$ Before $\overline{RAS}$ Counter Test Cycle)	40	–	50	–	ns	
48	t_{WTS}	Write Command Set-up Time(Test Mode In)	10	–	10	–	ns	
49	t_{WTH}	Write Command Hold Time(Test Mode In)	10	–	10	–	ns	
50	t_{WRP}	$\overline{WE}$ to $\overline{RAS}$ Precharge Time($\overline{CAS}$ Before $\overline{RAS}$ Cycle)	10	–	10	–	ns	
51	t_{WRH}	$\overline{WE}$ to $\overline{RAS}$ Hold Time($\overline{CAS}$ Before $\overline{RAS}$ Cycle)	10	–	10	–	ns	

AC CHARACTERISTICS IN TEST MODE NOTE 11

#	SYMBOL	PARAMETER	HY514100				UNIT	NOTES
			80		10			
			MIN.	MAX.	MIN.	MAX,		
52	t_{RC}	Random Read or Write Cycle Time	155	–	185	–	ns	
53	t_{RWC}	Read-Modify-Write Cycle Time	185	–	215	–	ns	
54	t_{PC}	Fast Page Mode Cycle Time	60	–	65	–	ns	
55	t_{PRWC}	Fast Page Mode Read-Modify-Write Cycle Time	90	–	95	–	ns	
56	t_{RAC}	Access Time from $\overline{RAS}$	–	85	–	105	ns	4, 9
57	t_{CAC}	Access Time from $\overline{CAS}$	–	30	–	30	ns	4, 9
58	t_{AA}	Access Time from Column Address	–	45	–	50	ns	4, 9
59	t_{CPA}	Access Time from $\overline{CAS}$ Precharge	–	55	–	60	ns	4
60	t_{RAS}	$\overline{RAS}$ Pulse Width	85	10K	105	10K	ns	
61	t_{RASP}	$\overline{RAS}$ Pulse Width (Fast Page Mode)	85	200K	105	200K	ns	
62	t_{RSH}	$\overline{RAS}$ Hold Time	30	–	30	–	ns	
63	t_{CSH}	$\overline{CAS}$ Hold Time	85	–	105	–	ns	
64	t_{CAS}	$\overline{CAS}$ Pulse Width	30	10K	30	10K	ns	
65	t_{RAL}	Column Address to $\overline{RAS}$ Lead Time	45	–	50	–	ns	
66	t_{CWD}	$\overline{CAS}$ to $\overline{WE}$ Delay Time	30	–	30	–	ns	8
67	t_{RWD}	$\overline{RAS}$ to $\overline{WE}$ Delay Time	85	–	105	–	ns	8
68	t_{AWD}	Column Address to $\overline{WE}$ Delay Time	45	–	50	–	ns	8

NOTES :

1. An initial pause of 200μs is required after power-up followed by 8 $\overline{RAS}$ cycles before proper device operation is achieved. In case of using internal refresh counter, a minimum of 8 $\overline{CAS}$ before $\overline{RAS}$ initialization cycles instead of 8 $\overline{RAS}$ cycles are required.
2. AC measurements assume t_T=5ns.
3. V_{IH}(min.) and V_{IL}(max.) are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL}.
4. Measured with a load equivalent to 2 TTL loads and 100pF.
5. t_{OFF}(max.) defines the time at which the output achieves the open circuit condition and are not referenced to output voltage levels.
6. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
7. These parameters are referenced to $\overline{CAS}$ leading edge in early write cycles and to $\overline{WE}$ leading edge in read-modify-write cycles.
8. t_{WCS}, t_{RWD}, t_{CWD} and t_{AWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristic only. If $t_{WCS} \geq t_{WCS}$(min.) the cycle is an early write cycle and data out pin will remain open circuit (high impedance) through the entire cycle : If $t_{RWD} \geq t_{RWD}$(min.), $t_{CWD} \geq t_{CWD}$(min.) and $t_{AWD} \geq t_{AWD}$(min.) the cycle is a read-modify-write cycle and data out will contain data read from the selected cell : If neither of the above sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.
9. Operation within the t_{RCD}(max.) limit insures that t_{RAC}(max.) can be met. t_{RCD}(max.) is specified as a reference point only : If t_{RCD} is greater than the specified t_{RCD}(max.) limit, then access time is controlled by t_{CAC}.
10. Operation within the t_{RAD}(max.) limit insures that t_{RAC}(max.) can be met. t_{RAD}(max.) is specified as a reference point only : If t_{RAD} is greater than the specified t_{RAD}(max.) limit, then access time is controlled by t_{AA}.
11. These specifications are applied to the test mode.

CAPACITANCE

(T_A=0℃ to 70℃, V_{DD}=5V±10%, f=1MHz)

SYMBOL	PARAMETER	MIN.	MAX.	UNIT
C_{IN1}	Input Capacitance (A_0~A_{10}, D_{IN})	–	5	pF
C_{IN2}	Input Capacitance ($\overline{RAS}$, $\overline{CAS}$, $\overline{WE}$)	–	7	pF
C_{OUT}	Output Capacitance (D_{OUT})	–	7	pF

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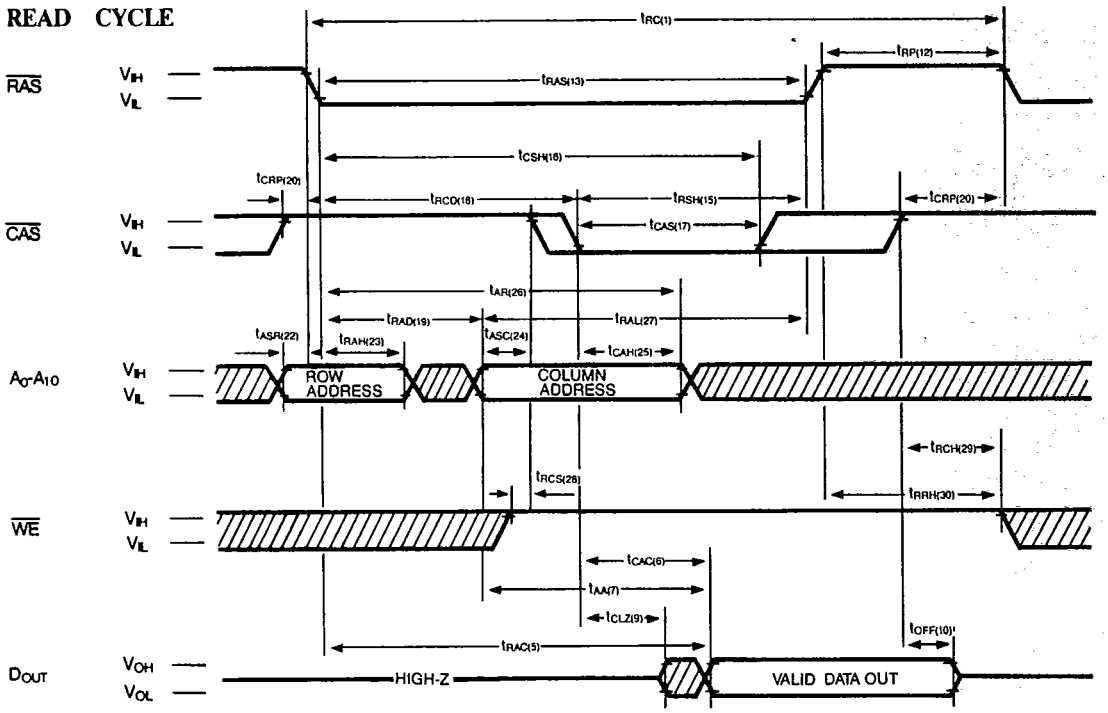
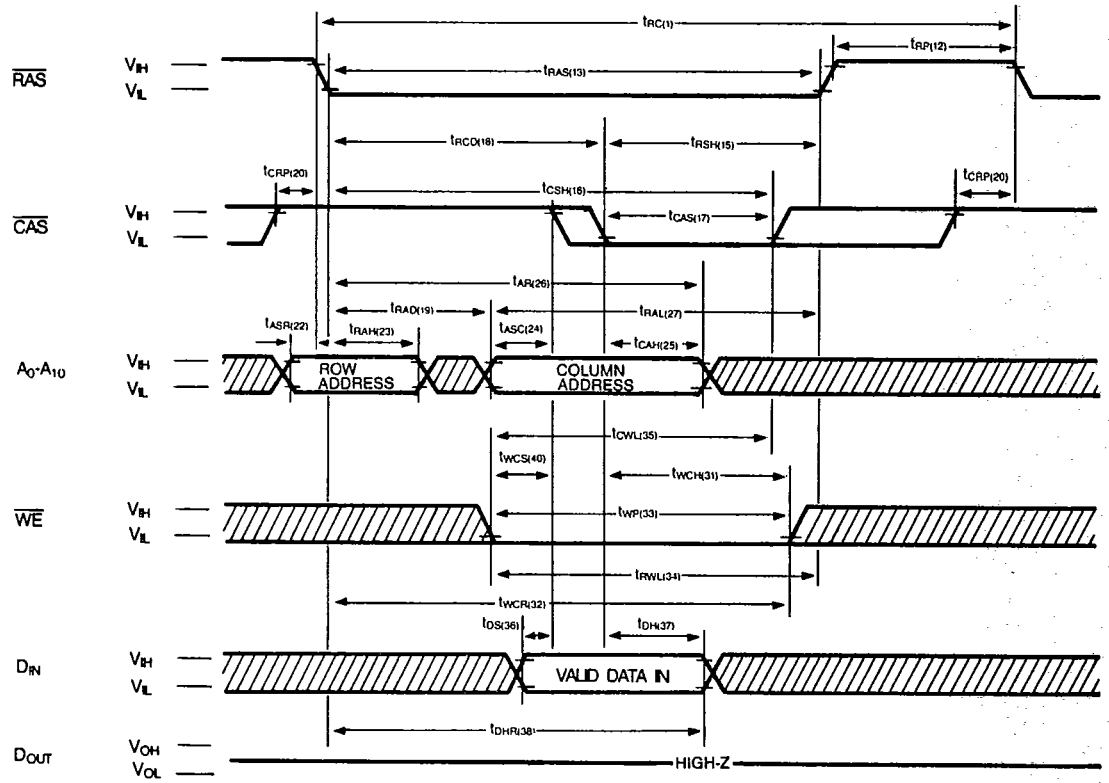
TIMING DIAGRAMS

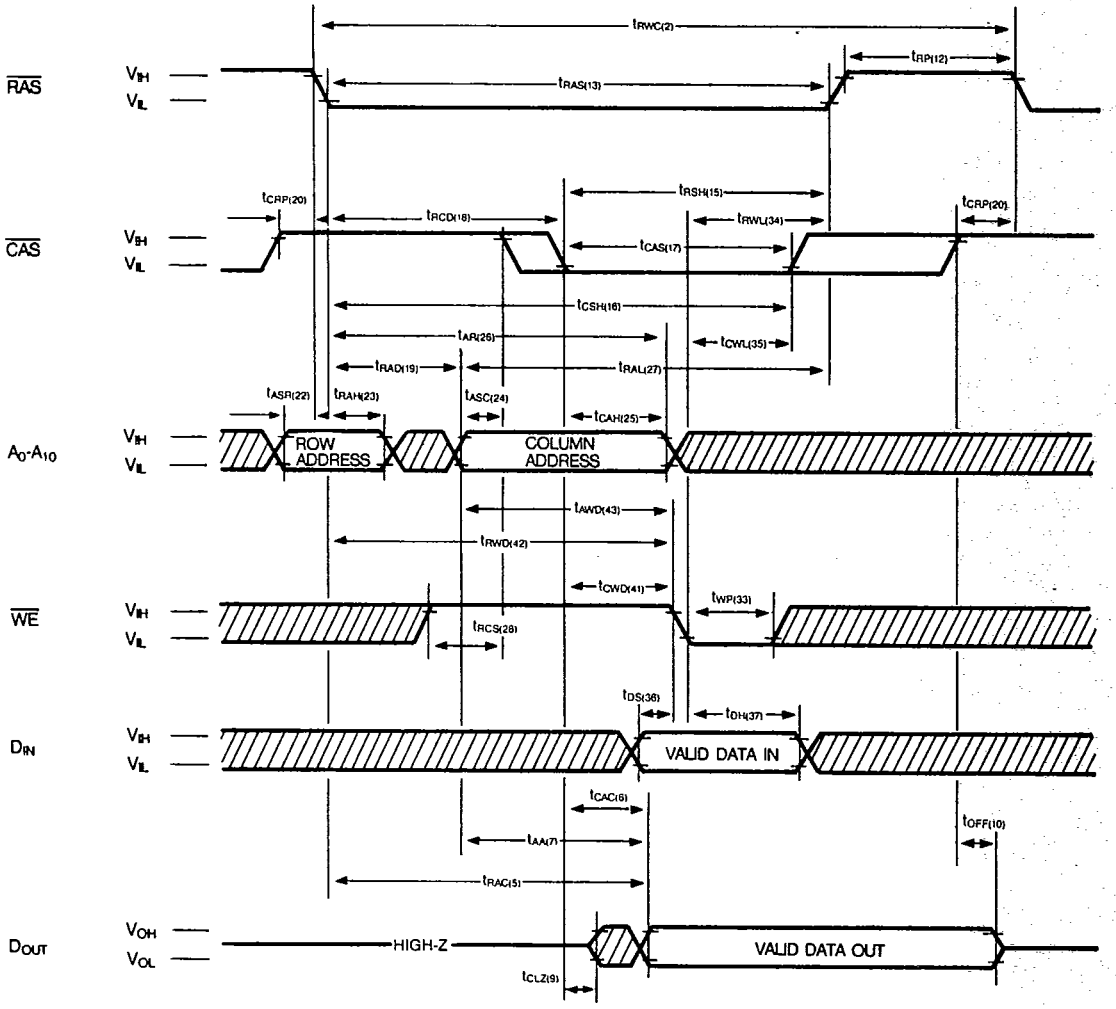
READ CYCLE



EARLY WRITE CYCLE



READ-MODIFY-WRITE CYCLE



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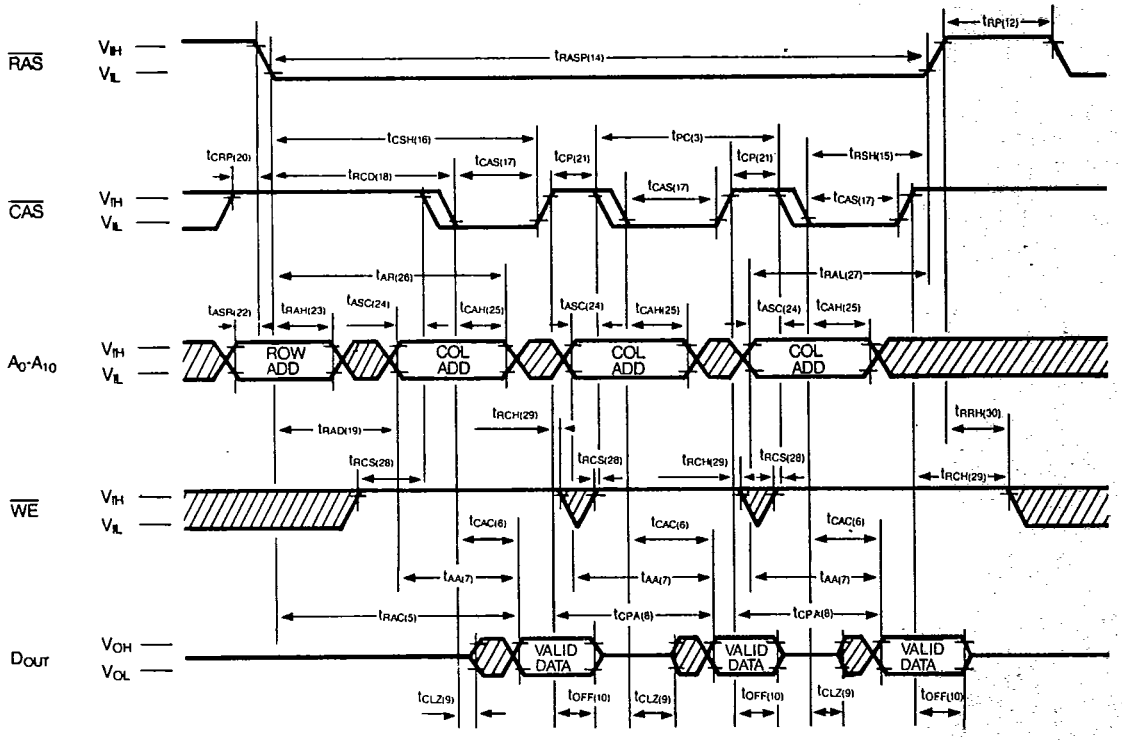
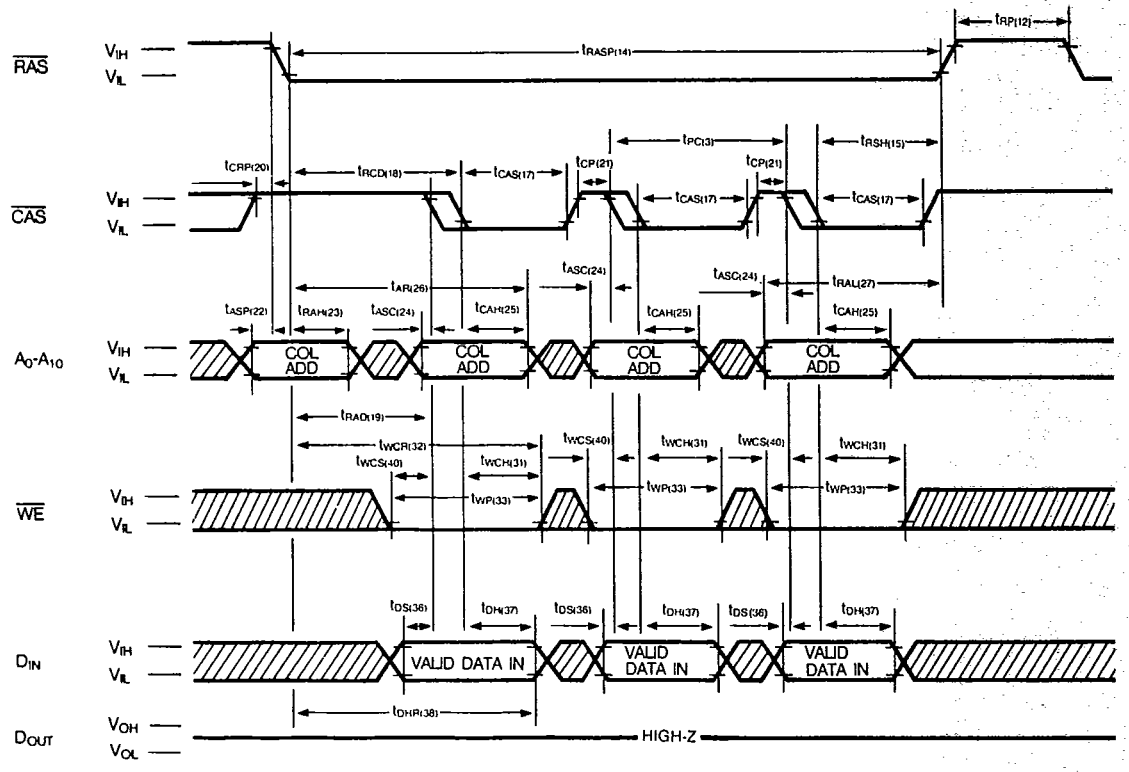
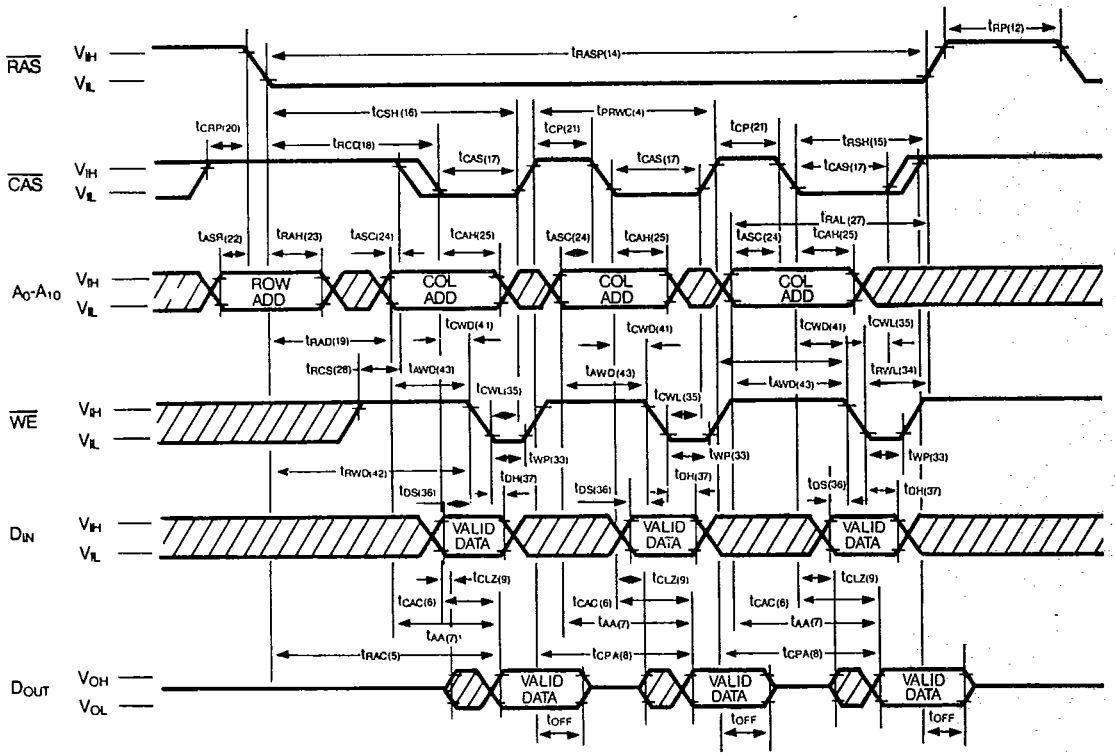
FAST PAGE MODE READ CYCLE



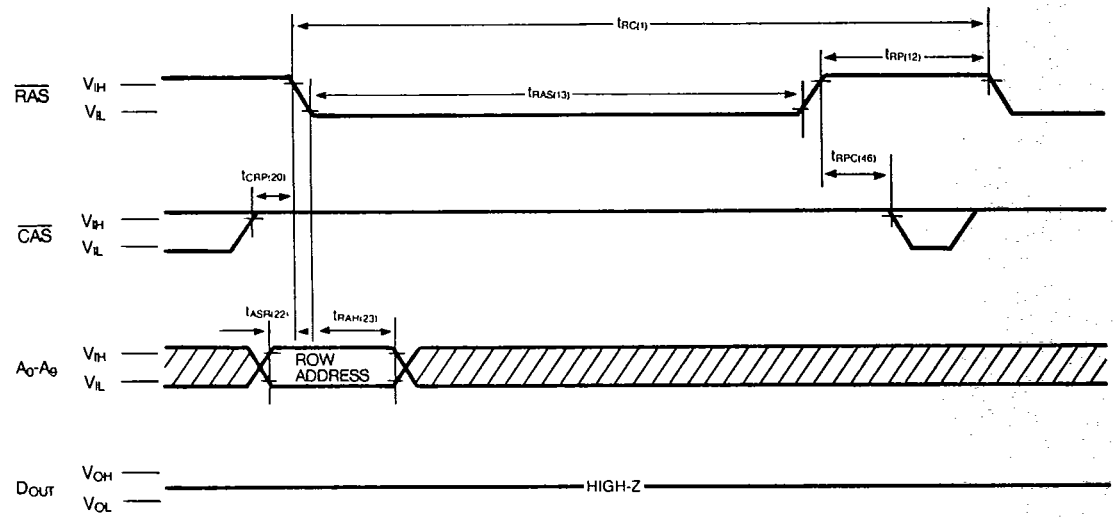
FAST PAGE MODE EARLY WRITE CYCLE



FAST PAGE MODE READ-MODIFY-WRITE

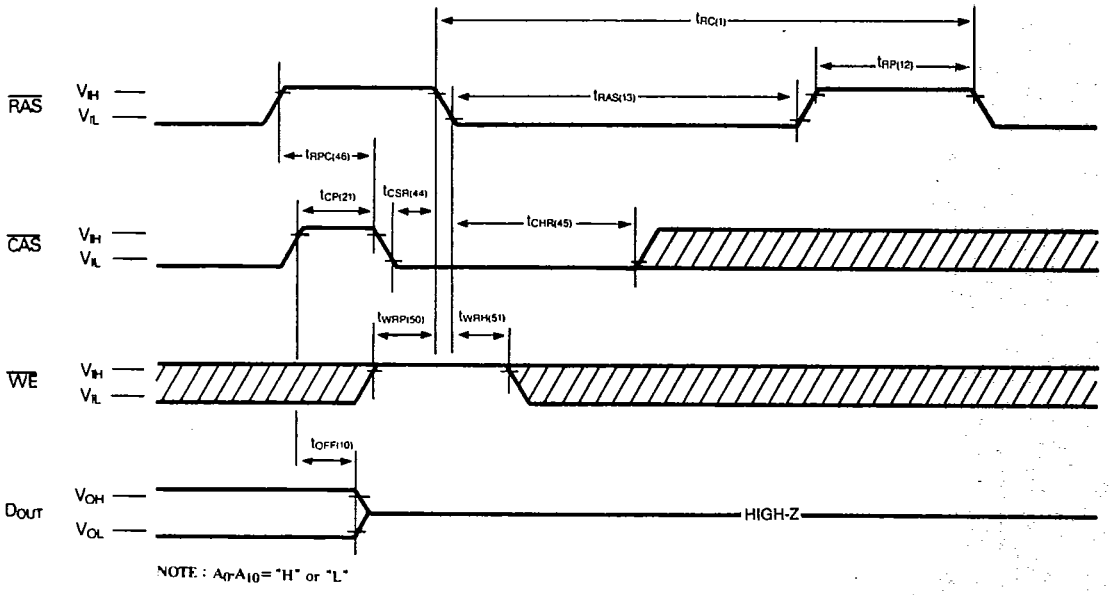


RAS-ONLY REFRESH CYCLE



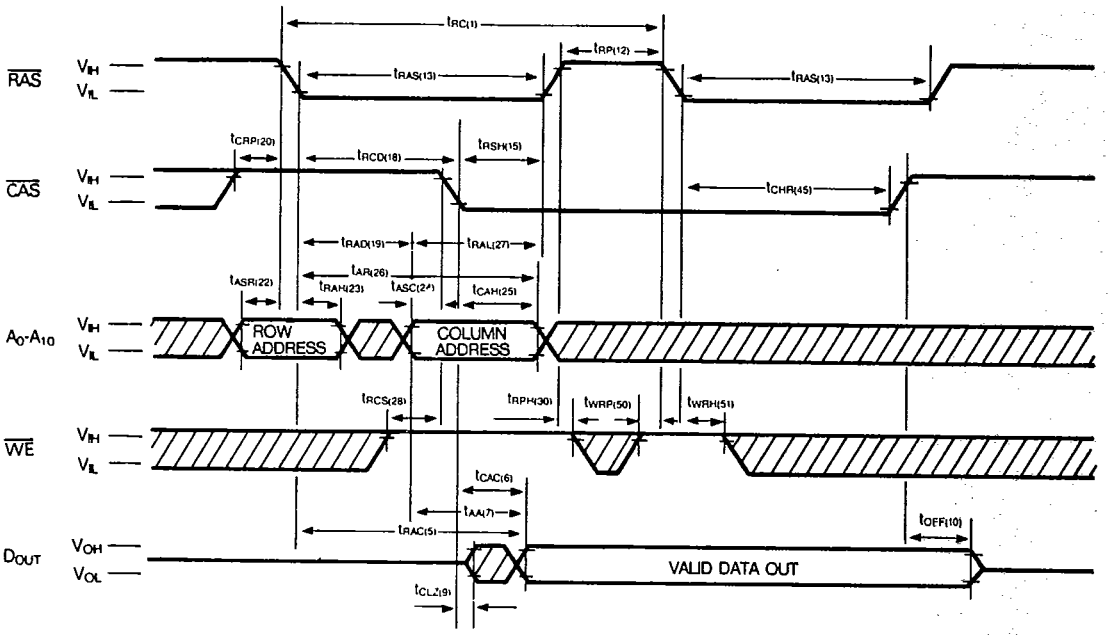
NOTE : $\overline{WE}$ and A_{10}="H" or "L"

CAS-BEFORE-RAS REFRESH CYCLE

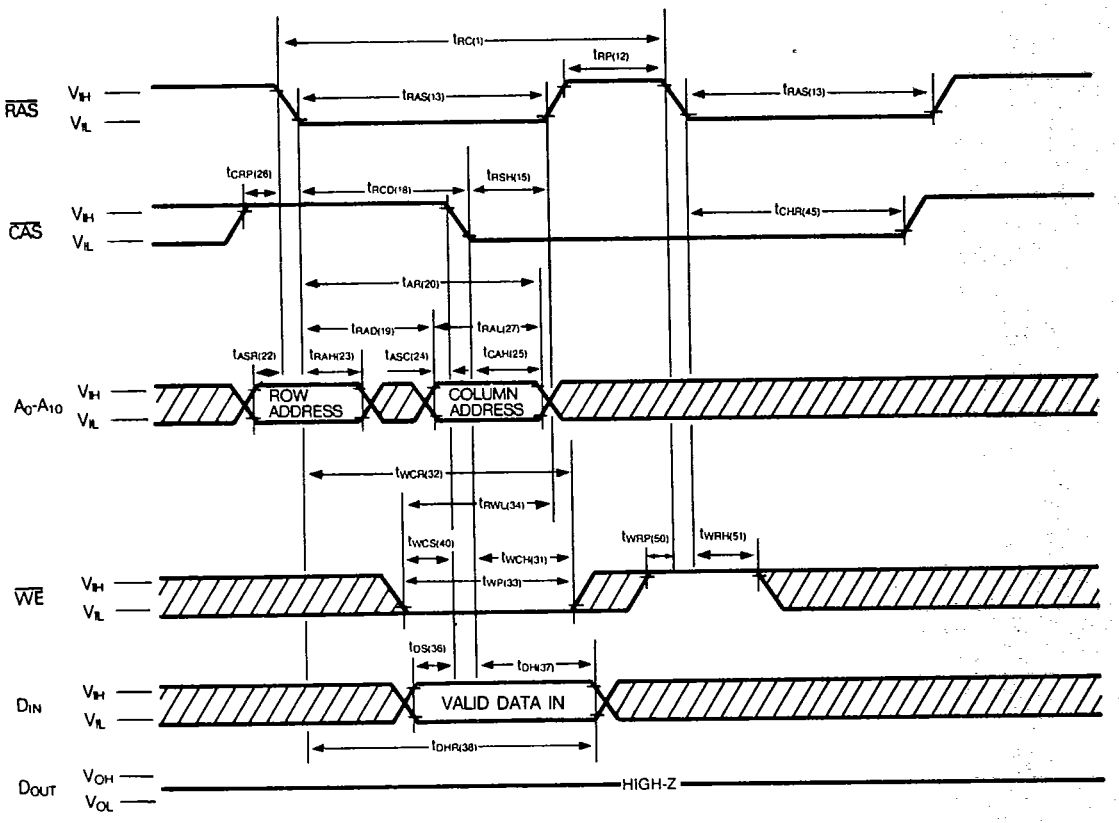


NOTE : A_0-A_{10} = "H" or "L"

HIDDEN REFRESH CYCLE (READ)



HIDDEN REFRESH CYCLE (WRITE)



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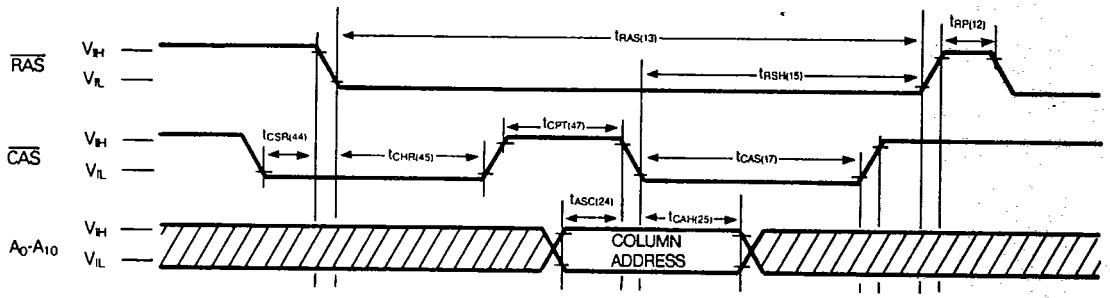
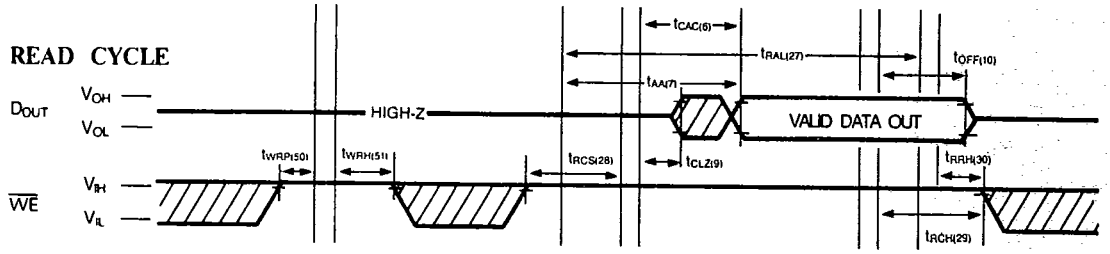
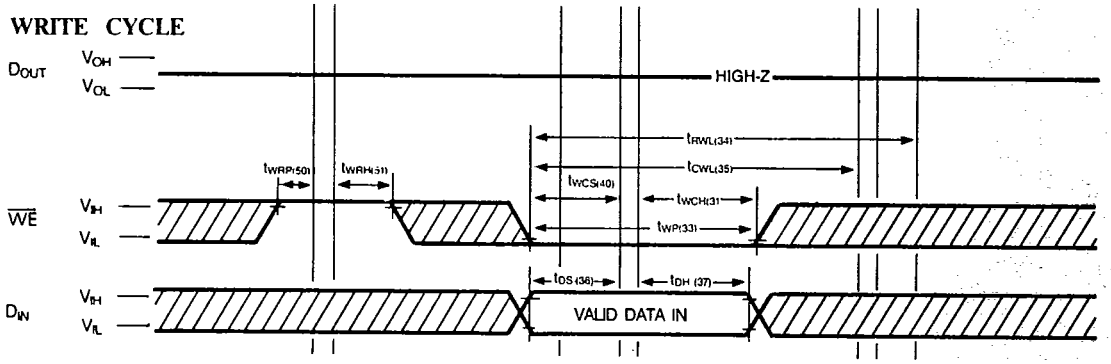
$\overline{CAS}$-BEFORE-$\overline{RAS}$ REFRESH COUNTER TEST CYCLE



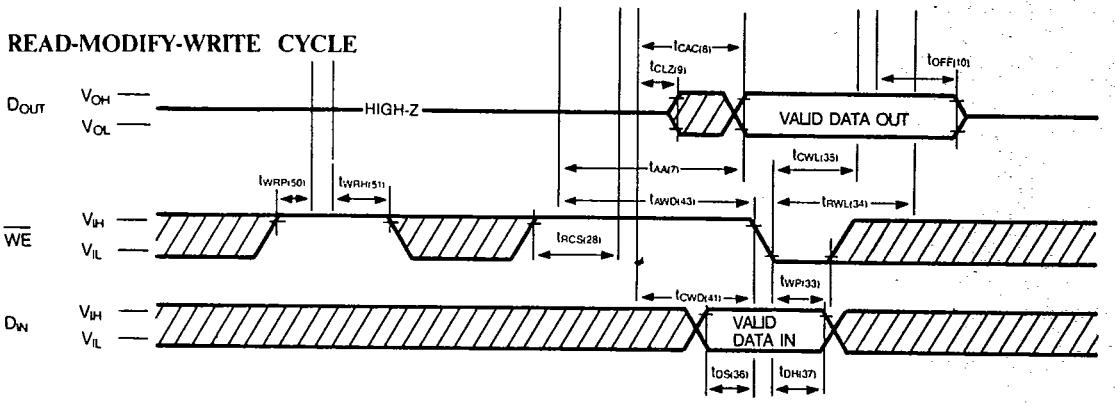
READ CYCLE



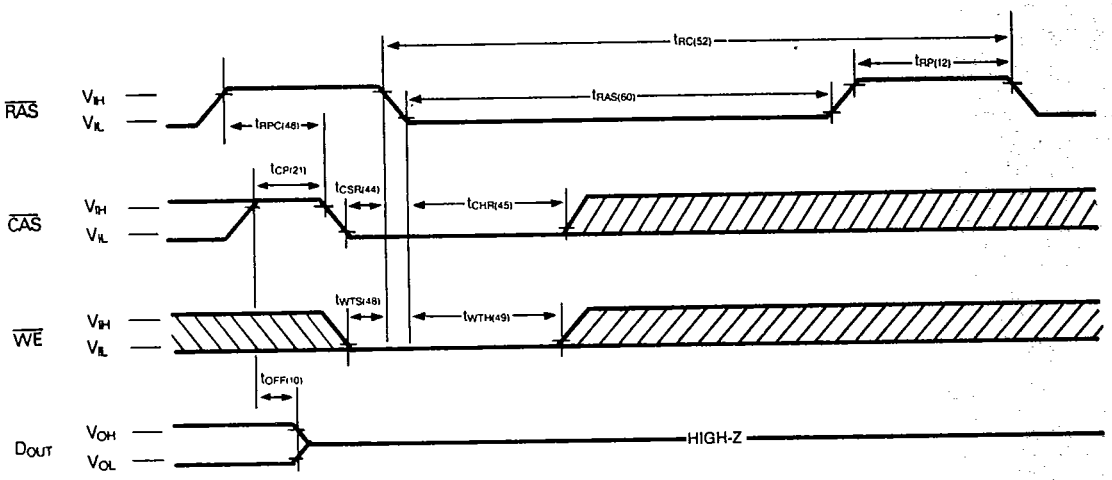
WRITE CYCLE



READ-MODIFY-WRITE CYCLE



TEST MODE IN CYCLE



NOTE : D_{IN} and A_0-A_{10} : "H" or "L"

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TEST MODE

The HY514100 is a DRAM organized 4,194,304 words by 1 bit and it is internally organized 524,288 words by 8 bits. In Test Mode, data are written into 8 sectors in parallel and read the same way. A_{10R}, A_{10C} and A_{0C} are not used. If all bits are equal after reading, the data output indicates 1. If any of the bits differed, the data out pin indicates 0. The following figure shows the block diagram of HY514100.

In Test Mode, the 4M×1 DRAM can be tested as if it were a 512K×8 DRAM.

$\overline{WE}$, $\overline{CAS}$-Before-$\overline{RAS}$ Cycle(Test Mode In) puts the device into Test Mode. And $\overline{CAS}$-Before-$\overline{RAS}$ Refresh Cycle or $\overline{RAS}$-Only Refresh Cycle puts it back into Normal Mode. The Test Mode function reduces test time to one-eighth of normal mode.

FIG. 1 BLOCK DIAGRAM IN TEST MODE